

*SPECIFICATION AMENDMENTS*

Replace the paragraph beginning at page 1, line 11 with:

In recent years, many system large-scale ~~integrations~~ integrated circuits (LSI), each having a central processing unit (CPU), a digital signal processor (DSP), a random-access memory (RAM) and the like, mounted on one chip, have been developed whereby the scale of the semiconductor integrated circuits is becoming larger. If such a system LSI with many components mounted on a single chip is to be designed from zero, it requires a long time and many man-~~hour~~ hours to design all the components of the system LSI. Therefore, designing experience in the past is often used and combined to make the designing process faster.

Replace the paragraph beginning at page 1, line 20 with:

If a system LSI is made using the designing experience ~~in~~ of the past, a method to test whether the system LSI is functioning properly or not also relies on the designing experience ~~in~~ of the past. For example, if components used in the system LSI are designed on the assumption that a one-path scan test is to be conducted, then when performing the test it is required to execute a one-path scan test.

Replace the paragraph beginning at page 2, line 16 with:

The second method is to input a scan pattern at high rate to shorten test time. This method is ~~disadvantageously~~ disadvantageous in view of the following reasons: